T. 7 X-Ray Microtomography System - CERTH

Specs:

Sizes up to 12x6 cm

Resolution @ µm

Investigation time-scale: hours/days

Possible problems: materials with same X-ray attenuation or materials with low attenuation (e.g. Si)

A 160 keV X-ray Microtomography System for non-invasive/non destructive material structure characterization.

Post mortem analysis: Micron resolution images of battery deformation after cycling (pouch cell, cylindrical)

Operando mode: An electrochemical cell for sub-micron morphological electrode/electrolyte interface (SEI) analysis

We can consider:

- Electrolyte decomposition, electrode volume expansion/contraction, electrode cracking and other morphological considerations
- Complementarity to **TEM/SEM**